

## Substrate patterning for liquid crystal alignment by optical interference

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Inhomogeneous liquid crystal (LC) alignment surfaces comprising a succession of microdomains favoring different LC alignment directions have been demonstrated for a number of optoelectronic applications. However, the prevalent method used to fabricate these surfaces is time consuming and produce functional areas that are too small for practical use. Here, we demonstrate a simple method based on photopatterning of an azodye layer with an interference pattern produced by intercepting two coherent UV beams. This method can produce alignment patterns within seconds with a practical size of  $\sim(0.5 \text{ cm})^2$ . © 2006 American Institute of Physics. [DOI: 10.1063/1.2209713]

There has been an enormous interest within the liquid crystal (LC) community to fabricate patterned LC alignment surfaces for their promises in numerous applications,<sup>1</sup> such as wide-viewing-angle display,<sup>2,3</sup> projection display,<sup>4</sup> optical grating,<sup>1,4-9</sup> bistable<sup>10</sup> and tristable<sup>11</sup> displays, no-bias bend-play display,<sup>12</sup> and alignment surfaces with tunable LC pretilt angle,<sup>13</sup> etc., as well as the corresponding ordering phenomena.<sup>14-17</sup> This has led to a proliferation of methods for making these surfaces, including atomic force microscopic (AFM) nanolithography,<sup>8,10-13,15-17</sup> polarization holography,<sup>1,9</sup> lithographic patterning of a photosensitive layer,<sup>2,18-21</sup> double rubbing,<sup>4</sup> microrubbing,<sup>4,5,7</sup> laser writing,<sup>22</sup> use of homeotropic and homogeneous polyimide mixtures,<sup>12</sup> etc. Among these methods, only the first method has been demonstrated for making patterns with inhomogeneous in-planned alignment and periods of  $\sim 1 \mu\text{m}$ , which is desirable in some of the aforementioned technologies.<sup>10-13</sup>

In this letter, we describe a method for making micro-patterned surfaces for LC alignment, in which an azodye film is exposed twice to an interference fringe pattern produced by intercepting two UV laser beams sequentially  $p$  and  $s$  polarized, with the interference pattern laterally shifted by a half period between the exposures. It produces patterns composed of alternating  $x$ - and  $y$ -alignment stripes (where  $x$  and  $y$  are the projections of the UV polarization direction  $\mathbf{P}$  in the film during  $p$  and  $s$  polarization, respectively). This method is simple, fast, and allows easy control of the pattern period and LC azimuthal alignment direction.

The azodye used is the so-called SD-1 supplied by Dainippon Ink and Chemicals, Japan. The procedure of preparing the SD-1 films on indium tin oxide (ITO) glass can be found in Ref. 23. The SD-1 molecules possess an UV absorption peak at 327 nm.<sup>23</sup> Illumination with linearly polarized UV near this wavelength produces LC alignment perpendicular to the polarization.<sup>24</sup>

Figure 1 shows our setup. The He-Cd laser produces cw UV beam with wavelength  $\lambda=325 \text{ nm}$  and linear polariza-

tion,  $\mathbf{P} \parallel \mathbf{y}$ . We first rotate  $\mathbf{P}$  by  $90^\circ$  by turning the optic axis of  $\lambda/2$ -plate-1 to  $45^\circ$  with respect to  $\mathbf{y}$ . Then the beam is split into two with one afterward passing through  $\lambda/2$ -plate-2, which has the optic axis along  $\mathbf{y}$ . Then the two ( $p$  polarized) beams are recombined to produce an interference fringe pattern to which the SD-1 film is exposed for time  $\tau_1$ . Then  $\mathbf{P}$  is returned to  $\mathbf{y}$  by adjusting  $\lambda/2$ -plate-1, causing the intercepting beams to be  $s$  polarized. With  $\mathbf{P} \parallel \mathbf{y}$ , the beam passing through  $\lambda/2$ -plate-2 acquires a phase change of  $\pi$  with respect to the first exposure thereby the fringes are shifted laterally by a half period. The SD-1 film is then exposed to this pattern for time  $\tau_2$ . The pattern period  $p$  is adjustable through the angle  $2\sigma$  ( $p=\lambda/2 \sin \sigma$ ). Lenses 1 and 2 expand the UV beam from  $\sim 1.5$  to  $\sim 5 \text{ mm}$ .

Figure 2 shows the optical images of LC cells constructed from four hence patterned SD-1 films (constituting the bottom wall; the upper wall is ITO glass coated with polyimide uniformly rubbed along  $\mathbf{y}$ ; the cell gap is  $25 \mu\text{m}$ ), placed between crossed polarizers. The LC is nematic 4'- $n$ -pentyl-4-cyanobiphenyl (5CB). Table I lists the exposure conditions used for the  $p=2, 1.67, \text{ and } 0.78 \mu\text{m}$  patterns. In Fig. 2, except for the  $p=0.78 \mu\text{m}$  cell, periodic dark and bright fringes are clearly visible, suggesting the LC alignment to be alternating between  $x$  and  $y$ . When the analyzer is rotated to the  $\phi=-45^\circ$  azimuthal direction, all four cells appear dark, confirming the bulk LC alignment to be uniform along  $\phi=+45^\circ$ . The uniform appearance of the  $p=0.78 \mu\text{m}$  cell can be due to the fringes being too narrow

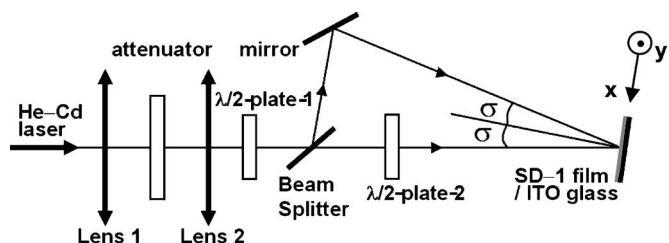


FIG. 1. Setup used to produce the inhomogeneous LC alignment pattern on the SD-1 films. The components labeled  $\lambda/2$ -plate- $i$  ( $i=1,2$ ) are half-wave plates.

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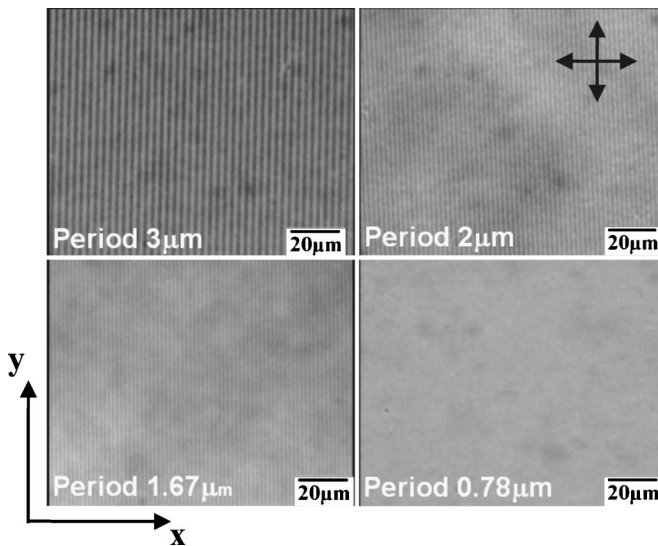


FIG. 2. Optical images of four representative LC cells constructed from SD-1 films patterned with different periods as shown. The double-sided arrows indicate the polarizer and analyzer directions used in taking the pictures.

to be resolved optically or the LC director field essentially uniform along  $\phi = +45^\circ$ .<sup>15</sup>

We measure the effective azimuthal surface energy  $W_{\phi, \text{eff}}$  for bulk LC alignment along  $\phi = +45^\circ$  of the  $p=2$ , 1.67, and 0.78  $\mu\text{m}$  patterns as detailed in Ref. 25. For comparison, we measure the azimuthal surface energy  $W_\phi$  of similarly exposed SD-1 films, but the UV polarization was held  $\parallel y$  in both exposures. The results show that  $W_{\phi, \text{eff}}/W_\phi$  is between 0.05 and 0.2 (Table I), which is consistent with the former result obtained from checkerboard-textured surfaces.<sup>15</sup>

Figure 3 displays plots of the average LC azimuthal alignment  $\phi$  vs  $\tau_2$  (solid circles) for the  $p=0.78$ , 1.67, and 2  $\mu\text{m}$  patterns subject to the otherwise same exposure conditions given in Table I. As seen,  $\phi$  (measured from  $x$ ) decreases monotonically from  $90^\circ$  to  $0^\circ$  as  $\tau_2$  increases. It means that the ratio of the summed area of the  $x$  alignment domain  $A_x$  to the total area of the film  $A_{\text{tot}}$  progressively increased from 0 to 1. According to a previous result,<sup>24</sup> the orientation of the azodye molecules in a freshly prepared SD-1 film is random. The first exposure produces azodye alignment along  $y$  with varying degrees [i.e.,  $\langle P_2(\theta) \rangle$  is varying; here,  $\langle \dots \rangle$  denotes ensemble averaging,  $P(\theta) = (1/2) \times (3 \cos^2 \theta - 1)$ , and  $\theta$  is the orientation of the azodye molecule with respect to  $\mathbf{P}$ ] according to the intensity profile of the fringes. The second exposure causes progressive rotation of the azodye molecules away from the alignment along  $y$ .

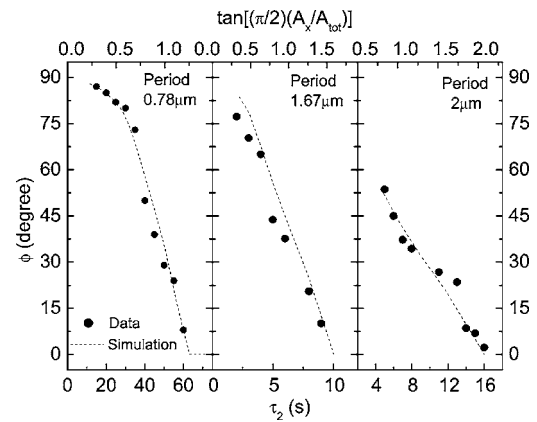


FIG. 3.  $\phi$  vs  $\tau_2$  for the  $p=2$ , 1.6, and 0.78  $\mu\text{m}$  patterns (solid circles, lower axis). The dashed lines are simulations of  $\phi$  plotted against  $\tan(\pi A_x/2A_{\text{tot}})$  (upper axis).

According to the diffusion model,<sup>24</sup> for azodye films with preexisting alignment, interactions among the azodye molecules cause an additional term,  $a\langle P_2(\theta) \rangle P_2(\theta - \theta_0)$ , to the effective potential governing the azodye alignment (where  $a$  is a constant and  $\theta_0$  is the direction of the existing alignment). For  $\theta_0 = 90^\circ$ , i.e., the preexisting alignment is  $\perp \mathbf{P}$ , the incident UV must possess an intensity larger than a threshold  $\propto 3a\langle P_2(\theta) \rangle/k_B T$  before the original azodye alignment can be altered.

We examine the validity of this prediction. The SD-1 film is exposed to uniform UV irradiation twice with the same sequence of polarization as before. The first and second exposure times are fixed at 24 and 6 s, respectively. The second exposure intensity  $I_2$  is kept at 2.82  $\text{mW}/\text{cm}^2$  and the first exposure intensity  $I_1$  varied. The result, plotted as  $\phi$  vs  $I_1$ , is displayed in Fig. 4 by the solid squares. As seen, the second exposure begins to overwrite the alignment effect of the first exposure when  $I_1$  falls below 2.2  $\text{mW}/\text{cm}^2$ . But a similar experiment with  $I_2$  increased to 6.18  $\text{mW}/\text{cm}^2$  (open circles) shows that overwriting occurs even for much larger  $I_1$ .

This result implies that the ultimate growth of the  $x$  alignment domains shown in Fig. 3 cannot occur by a simple rotation of the azodye molecules from  $y$  to  $x$  energized by the second exposure. We propose that it occurs by a systematic progression of the domain walls where  $\langle P_2(\theta) \rangle = 0$  so that no threshold intensity is required for overwriting. Consider the conservation of energy when a domain wall moves to expand the  $x$  domains at the expense of the  $y$  domains,

TABLE I. UV exposure conditions and azimuthal surface energies.

Period ( $\mu\text{m}$ )	First UV exposure ( $\downarrow$ )		Second UV exposure ( $\leftrightarrow$ )		Azimuthal surface energy ( $10^{-5} \text{ J}/\text{m}^2$ )	
	Average UV intensity ( $\text{mW}/\text{cm}^2$ )	$\tau_1$ (s)	Average UV intensity ( $\text{mW}/\text{cm}^2$ )	$\tau_2$ (s)	Inhomogeneous alignment ( $W_{\phi, \text{eff}}$ )	Uniform alignment ( $W_\phi$ )
2	1.94	24	2.95	6	0.25 $\pm$ 0.05	1.95 $\pm$ 0.4
1.67	2.02	16	2.99	5	0.15 $\pm$ 0.05	1.64 $\pm$ 0.4
0.78	0.45	110	0.46	43	0.08 $\pm$ 0.05	1.43 $\pm$ 0.4

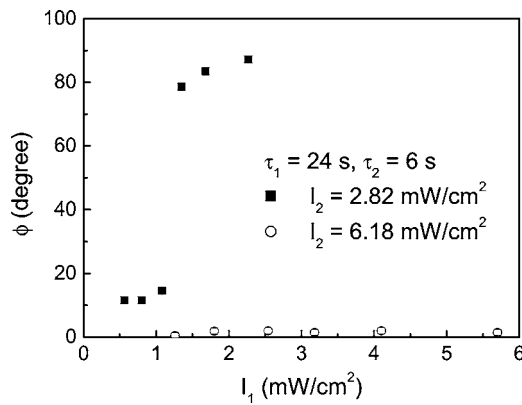


FIG. 4. Average LC azimuthal alignment found on SD-1 films exposed to a uniform UV laser beam polarized along  $x$  for 24 s with different intensities  $I_1$  (plotted as the abscissa) followed by a second uniform exposure with UV polarization changed to  $y$  for 6 s and a fixed intensity of  $I_2$ , set to 2.82 and 6.18  $\text{mW}/\text{cm}^2$  for the two measurement series shown.

$$(\chi_{\parallel} - \chi_{\perp}) \frac{E(x)^2 d|x|}{2 dt} h w = - \frac{dU(\theta)}{d\theta} \frac{d\theta}{dt}, \quad (1)$$

where  $\chi_{\parallel}$  and  $\chi_{\perp}$  are the electric susceptibilities of the SD-1 layer  $\parallel$  and  $\perp$ , respectively, to the electric field  $E(x)$  of the UV light,  $x$  is the coordinate of the domain wall,  $t$  is the time,  $h$  and  $w$  are, respectively, the thickness and width (along  $y$ ) of the SD-1 layer, and  $U(\theta) = (1/2)I_2(x)ahw\tau \cos^2 \theta$  is the potential energy governing the azodye alignment.<sup>24</sup> [Here,  $\alpha$  ( $\text{cm}^{-1}$ ) is the absorption coefficient of the SD-1 layer and  $\tau$  is the relaxation time for the rotation of the azodye molecules.] The absolute sign in Eq. (1) ensures that the  $x$  domains always expand at the expense of the  $y$  domains to lower the energy. By adopting  $E(x)^2 \propto I_2(x)$  and  $d\theta/dt \propto I_2(x)$ ,<sup>24</sup> Eq. (1) leads to  $d|x|/dt \propto I_2(x) \propto \cos^2(\pi x/p)$ . Integrating once gives  $\pi|x|/p \propto \tan^{-1} t$ . Since the  $x$  domains expand through simultaneous advancement of the left and right walls,  $A_x/A_{\text{tot}} = 2|x|/p$  and  $t \propto \tan(\pi A_x/2A_{\text{tot}})$ .

We simulate the variation of  $\phi$  with  $\tan(\pi A_x/2A_{\text{tot}})$  by using the model of Ref. 15 and assuming the values of  $W_{\phi}$  in Table I. The results are displayed by dashed lines in Fig. 3. Clearly, the simulations provide a good description of the data. The model also implies that the time scale for complete overwrite of the first alignment effect varies linearly with  $p$  and  $(d\theta/dt)^{-1} (\propto I_2^{-1})$  from above). From Table I, the ratio  $p/I_2$  for  $p=2: 1.67: 0.78 \mu\text{m}$  patterns is 0.40: 0.33: 1, which agrees reasonably well with the ratio for the observed  $\tau_2$  for complete overwrite, i.e., 0.27: 0.15: 1 (Fig. 3). The system-

atically shorter measured time than predicted may come from the assumption that  $d\theta/dt \propto I_2(x)$ , which is due to calculations assuming the incident UV to be uniform.<sup>24</sup> This overlooks torques that can arise from elastic recoil from the inhomogeneous azodye field and cause the discrepancy.

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